

FORM PTO-1449

INFORMATION DISCLOSURE STATEMENT

ATTY. DOCKET NO.
1857.1460000APPLICATION NO.
09/339,506FIRST NAMED INVENTOR
Matthew E. HansenFILING DATE
June 24, 1999ART UNIT
2877

U.S. PATENT DOCUMENTS

| EXAMINER INITIAL | DOCUMENT NUMBER | DATE | NAME | CLASS | SUB-CLASS | FILING DATE |
|---------------------|--------------------|------------|------------------------|-------|-----------|-------------|
| AA1 | | | | | | |
| AB1 | | | | | | |
| AC1 | 4,289,959 | 09/15/1981 | Takayama <i>et al.</i> | | | |
| AD1 | 5,814,425 | 09/29/1998 | Kataoka <i>et al.</i> | | | |
| AE1 | | | | | | |
| AF1 | | | | | | |
| AG1 | | | | | | |
| AH1 | | | | | | |
| AI1 | | | | | | |
| AJ1 | | | | | | |
| AK1 | | | | | | |

FOREIGN PATENT DOCUMENTS

| EXAMINER INITIAL | DOCUMENT NUMBER | DATE | COUNTRY | CLASS | SUB-CLASS | TRANSLATION |
|---------------------|--------------------|------------|---------|-------|-----------|-------------|
| AL1 | | | | | | Yes No |
| AM1 | | | | | | Yes No |
| AN1 | EP 0 628 806 A2 | 04/28/1994 | Europe | | | Yes No |
| AO1 | | | | | | Yes No |
| AP1 | | | | | | Yes No |

OTHER (Including Author, Title, Date, Pertinent Pages, etc.)

| | | |
|----|---|--|
| AR | 1 | |
| AS | 1 | |
| AT | 1 | |

EXAMINER

DATE CONSIDERED

6/30/04

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

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|---------------------|--------------------|------|------|-------|-----------|-------------|
| | AA2 | | | | | |
| | AB2 | | | | | |
| | AC2 | | | | | |
| | AD2 | | | | | |
| | AE2 | | | | | |
| | AF2 | | | | | |
| | AG2 | | | | | |
| | AH2 | | | | | |
| | AI2 | | | | | |
| | AJ2 | | | | | |
| | AK2 | | | | | |

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| EXAMINER INITIAL | DOCUMENT NUMBER | DATE | COUNTRY | CLASS | SUB-CLASS | TRANSLATION |
|---------------------|--------------------|------|---------|-------|-----------|-------------|
| | AL2 | | | | | Yes No |
| | AM2 | | | | | Yes No |
| | AN2 | | | | | Yes No |
| | AO2 | | | | | Yes No |
| | AP2 | | | | | Yes No |

OTHER (Including Author, Title, Date, Pertinent Pages, etc.)

| | | |
|----|---|---|
| AR | 2 | Copy of European Search Report for European Appln. 00112970.9 mailed April 14, 2004. |
| AS | 2 | J.P. Kirk and C.J. Progler, "Application of Blazed Gratings for Determination of Equivalent Primary Azimuthal Aberrations", March 1999, Optical Microlithography XII, vol. 3679, pp. 70-76. |
| AT | 2 | |

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